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Contents

Editorial vii

Committees and sponsors viii

Contents ix

0. Overview

Impact of next-generation synchrotron radiation sources on materials research
G.K. Shenoy 1

Applied and industrial activities at the ESRF: Present status and future development
J. Doucet 10

1. Elastic interaction

1.1. Diffraction

1.1.1. Microbeam diffraction

Measurement of minute local strain in semiconductor materials and electronic devices by using a highly parallel X-ray microbeam
J. Matsui, Y. Tsusaka, K. Yokoyama, S. Takeda, M. Katou, H. Kurihara, K. Watanabe, Y. Kagoshima and S. Kimura 15

Estimation of bonded silicon-on-insulator wafers by means of diffractometry using a parallel X-ray microbeam
Y. Tsusaka, M. Urakawa, K. Yokoyama, S. Takeda, M. Katou, H. Kurihara, F. Yoshida, K. Watanabe, Y. Kagoshima and J. Matsui 19

1.1.2. High-energy diffraction

High-energy X-ray diffraction studies of disordered materials
S. Kohara and K. Suzuya 23

Structural analysis of 1-ethyl-3-methylimidazolium bifluoride melt
K. Matsumoto, R. Hagiwara, Y. Ito, S. Kohara and K. Suzuya 29

The structural analysis of manganese borate glass by high-energy X-ray diffraction measurement
A. Kajinami, T. Kotake, S. Deki and S. Kohara 34

High-resolution texture imaging with hard synchrotron radiation in the moving area detector technique
L. Wcislak, H.J. Bunge, H. Klein, U. Garbe and J.R. Schneider 38

1.1.3. Powder diffraction

In situ analysis of phase transformation in sol–gel cogelified nanopowder mixture of Al_2O_3 and TiO_2 using synchrotron X-ray radiation diffraction experiments
A. Jianu, L. Stanciu, J.R. Groza, Ch. Lathe and E. Burkel 44

PII: S0168-583X(02)02163-8

Study of crystal structure at high temperature phase in KIO_3 crystal by synchrotron powder X-ray diffraction
H. Kasatani, S. Aoyagi, Y. Kuroiwa, K. Yagi, R. Katayama and H. Terauchi 49
Mechanism of degradation of surface hardening at elevated temperature in TiAlV-alloys by in situ synchrotron radiation diffraction
F. Berberich, W. Matz, U. Kreißig, N. Schell and A. Mücklich 54
In situ high-pressure and high-temperature diffraction experiments on pure and Ag-doped TiO_2 nanopowders
M. Stir, T. Traykova, R. Nicula, E. Burkel, C. Baehtz, M. Knapp and C. Lathe 59
Structural studies of $Ba_{6-3x}Nd_{8+2x}Ti_{18}O_{54}$ microwave dielectric ceramics at $T = 10$–295 K
C.C. Tang, M.A. Roberts, F. Azough and R. Freer 64

1.1.4. Topography
Formation of high energy white microbeam and its application to spectro-scattering topography
Y. Chikaura, K. Kajiwara, K. Morita, K. Mizuno, S. Iida, S. Kawado and Y. Suzuki 67
White beam X-ray topography at the synchrotron light source ANKA, Research Centre Karlsruhe
A.N. Danilewsky, R. Simon, A. Fauler, M. Fiederle and K.W. Benz 71
Stroboscopic topographies on iron borate crystal in 9.6 MHz rf magnetic field
T. Mitsui, Y. Imai and S. Kikuta 75
Low temperature Laue topography of strontium titanate at SPring-8
T. Ozaki, I. Fujimoto, K. Mizuno, S. Iida, K. Kajiwara, T. Taira, J. Yoshimura, T. Shimura and Y. Chikaura 81
High resolution X-ray Laue topography of thick quartz crystals at SPring-8
C.K. Suzuki, A.H. Shinohara, C.Q. Hiramatsu, J.-i. Yoshimura, J.B. Reid, K. Kajiwara and Y. Chikaura 85

1.2. Scattering

1.2.1. Scattering
SAXS/WAXS experiments using extreme sample environments
W. Bras 90
SAXS/WAXS and XAFS studies of zeolite stability
G.N. Greaves, F. Meneau and G. Sankar 98
Applications of micro-SAXS/WAXS to study polymer fibers
C. Riekel 106
Setup for in situ WAXS/SAXS studies of the formation and growth of Bi nanodroplets and the melting of Bi nanocrystals using synchrotron radiation
G. Kellermann, A.F. Craievich, R. Neuenschwander and T.S. Plivelic 112
Structure of luminescent mono and di-urethanesil nanocomposites doped with Eu^{3+} ions
K. Dahmouche, M.C. Gonçalves, C.V. Santilli, V. de Zea Bermudez, L.D. Carlos and A.F. Craievich 117
Use of anomalous scattering for synchrotron X-ray reflectivity studies of Fe–Cr and Co–Cu double layers
F. Prokert, N. Schell and A. Gorbunov 123

1.2.2. Reflectometry
Characterization of molybdenum/silicon X-ray multilayers
M. Nayak, M.H. Modi, G.S. Lodha, A.K. Shrivastava, P. Tripathi, A.K. Sinha, K.J.S. Sawhney and R.V. Nandedkar 128
Growth mode and texture development in TiN films during magnetron sputtering – An in situ synchrotron radiation study
N. Schell, J. Bottiger, W. Matz and J. Chevallier 133
Specular and non-specular X-ray reflection from a single-crystal molybdenum mirror surface
M. Mizusawa and K. Sakurai 139

2. Inelastic interaction

2.1. Inelastic scattering

Dynamics of new materials probed by inelastic X-ray scattering
E. Burkel 143
Lattice dynamics of Al-based quasicrystals studied by high-resolution inelastic X-ray scattering with synchrotron radiation
E. Burkel, R. Nicula, U. Ponkratz, H. Sinn, A. Alatas and E.E. Alp 151
A structural study of effects of NiP seed layer on the magnetic properties of CoCrPt/Ti/NiP perpendicular magnetic films
C.J. Sun, G.M. Chow, J.P. Wang, E.W. Soo, D.Y. Noh, J.H. Je and Y.K. Hwu 156
Phonon dynamics of liquid Si – inelastic X-ray scattering studies
S. Hosokawa, J. Greif, F. Demmel and W.-C. Pilgrim 161
Rigidity transitions and intermediate structures of Ge–Se glasses – An anomalous X-ray scattering study
S. Hosokawa, Y. Wang, M. Sakurai, J.-F. Bérar, W.-C. Pilgrim and K. Murase 165

2.2. Absorption

2.2.1. Hard X-ray absorption fine structure spectroscopy

X-ray absorption studies of atomic environments in semiconductor nanostructures
F. Boscherini 169
Local structure of Ge/Si nanostructures: Uniqueness of XAFS spectroscopy
A.V. Kolobov, H. Oyanagi, A. Frenkel, I. Robinson, J. Cross, S. Wei, K. Brunner, G. Abstreiter, Y. Maeda, A. Shklyaev, M. Ichikawa, S. Yamasaki and K. Tanaka 174
EXAFS measurements of metal-decorated nanocavities in Si
G. de M. Azevedo, M.C. Ridgway, J. Betlehem, K.M. Yu, C.J. Glover and G.J. Foran 179
Electronic structures of $La_{0.7-x}Cs_xCa_{0.3}MnO_3$ probed by X-ray absorption spectroscopy
U. Chandra, J.C. Jan, J.W. Chiou, K. Asokan and W.F. Pong 185
An EXAFS and XANES study of MBE grown Cu-doped ZnO
P. Fons, A. Yamada, K. Iwata, K. Matsubara, S. Niki, K. Nakahara and H. Takasu 190
Structure of amorphous silicon investigated by EXAFS
C.J. Glover, G.J. Foran and M.C. Ridgway 195
Experimental and theoretical study of the electronic structure of Fe_3Al
L.-S. Hsu, G.Y. Guo and Y.-K. Wang 200
Double resonance capacitance spectroscopy (DORCAS): A new experimental technique for assignment of X-ray absorption peaks to surface sites of semiconductor
M. Ishii 205
Influence of Cr and Mo on the passivation of stainless steel 430 (18Cr) and 444 (18Cr–2Mo): In situ XANES study
S.J. Doh, J.H. Je, J.S. Kim, K.Y. Kim, H.S. Kim, Y.D. Lee, J.M. Lee and Y. Hwu 211
XAFS study of an intermetallic $TiFe_{0.95}Zr_{0.03}Mo_{0.02}$ system for CO_2 conversion
V.V. Kriventsov, D.I. Kochubey, M.V. Tsodikov, J.A. Navio, M.C. Hidalgo, G. Colón, Yu.V. Maksimov and I.P. Suzdalev 216
EXAFS study of ion beam mixed Fe/Al multilayers
I. Arčon, M. Mozetič, A. Zalar, A. Kodre and J. Jagielski 222
Fluorescence extended X-ray absorption fine structure analysis of half-metallic ferromagnet "zinc-blende CrAs" grown on GaAs by molecular beam epitaxy
H. Ofuchi, M. Mizuguchi, K. Ono, M. Oshima, H. Akinaga and T. Manago 227
Fluorescence XAFS study on local structures around Tb ions implanted in SiO_2 on Si
H. Ofuchi, Y. Imaizumi, H. Sugawara, H. Fujioka, M. Oshima and Y. Takeda 231

Common structure in amorphised compound semiconductors
M.C. Ridgway, G. de M. Azevedo, C.J. Glover, K.M. Yu and G.J. Foran 235
Orientation and charge transfer upon adsorption of ethanethiol on Cu(111) surface at 85 K
S.A. Sardar, J.A. Syed, E. Ikenaga, S. Yagi, T. Sekitani, S. Wada, M. Taniguchi and K. Tanaka 240
Adsorption behavior of sulfur-containing amino acid molecule on transition metal surface studied by S K-edge NEXAFS
S. Yagi, K. Matsumura, Y. Nakano, E. Ikenaga, S.A. Sardar, J.A. Syed, K. Soda, E. Hashimoto, K. Tanaka and M. Taniguchi 244

2.2.2. Soft X-ray absorption spectroscopy
X-ray absorption near edge structure of DNA bases around oxygen and nitrogen K-edge
K. Fujii, K. Akamatsu, Y. Muramatsu and A. Yokoya 249
Observation of acceptor level of p-type $SrTiO_3$ by high-resolution soft-X-ray absorption spectroscopy
T. Higuchi, T. Tsukamoto, S. Yamaguchi, K. Kobayashi, N. Sata, M. Ishigame and S. Shin 255
Soft X-ray emission and absorption spectroscopy in the Si *L* region of polysilanes
Y. Muramatsu, M. Fujino, T. Yamamoto, E.M. Gullikson and R.C.C. Perera 260
Excited states of perfluorinated oligo(*p*-phenylene) by inner-shell excitation
K.K. Okudaira, K. Ohara, H. Setoyama, T. Suzuki, Y. Sakamoto, M. Imamura, S. Hasegawa, K. Mase and N. Ueno 265
Anisotropic absorption spectra of polyester films in the ultraviolet and vacuum ultraviolet regions
I. Ouchi, I. Nakai and M. Kamada 270
Partial ion yield and NEXAFS of 2-(perfluorooctyl)ethanethiol self-assembled monolayer: Comparison with PTFE results
H. Setoyama, S. Kera, T. Murase, M. Imamura, K. Mase, K.K. Okudaira, M. Hara and N. Ueno ... 275
Study of anomalous temperature dependence of itinerant holes in under- and overdoped $La_{2-x}Sr_xCuO_4$ single crystals using polarised soft X-ray absorption spectroscopy
R.K. Singhal, N.L. Saini, S. Dalela, B. Sekhar, D.C. Jain and K.B. Garg 280
The electronic structure and spectral properties of ZnO and its defects
P.S. Xu, Y.M. Sun, C.S. Shi, F.Q. Xu and H.B. Pan 286
Surface structure of α-Fe_2O_3 nanocrystal observed by O K-edge X-ray absorption spectroscopy
J. Zhang, Z.Y. Wu, K. Ibrahim, M.I. Abbas and X. Ju 291

2.2.3. Magnetic methods
Synchrotron X-ray magnetic scattering
W.G. Stirling 295
Magnetism in heterogeneous thin film systems: Resonant X-ray scattering studies
J.B. Kortright, J.S. Jiang, S.D. Bader, O. Hellwig, D.T. Marguiles and E.E. Fullerton 301
Magnetic circular dichroism of $LaMn_{1-x}Al_xO_{3+\delta}$ series of samples
A. Banerjee, S.M. Chaudhari, R.V. Krishnan, B.A. Dasannacharya, T. Muro, Y. Saitoh, S. Imada and S. Suga 308
Soft X-ray magneto-optics in lanthanides at the $N_{4,5}$- and $M_{4,5}$-thresholds
K. Starke, F. Heigl, J.E. Prieto, O. Krupin and G. Kaindl 313
Measurements of temperature dependence of "localized susceptibility"
H. Shiozawa, T. Miyahara, H. Ishii, Y. Takayama, K. Obu, T. Muro, Y. Saitoh, T.D. Matsuda, H. Sugawara and H. Sato 318

2.2.4. Infrared spectroscopy
Dynamics of GaAs photocarriers probed with pulsed infrared synchrotron radiation
G.L. Carr 323
Infrared spectral change in 2-deoxy-D-ribose by irradiation with monochromatic photons around oxygen K-edge
K. Akamatsu, K. Fujii and A. Yokoya 328

2.2.5. Modification of materials by irradiation

Materials for LiGA and LiGA-based microsystems
J. Hormes, J. Göttert, K. Lian, Y. Desta and L. Jian 332
Synchrotron X-ray induced solution precipitation of nanoparticles
H.J. Lee, J.H. Je, Y. Hwu and W.L. Tsai 342
Study of Auger effect in DNA when bound to molecules containing platinum. A possible application to hadrontherapy
K. Kobayashi, N. Usami, I. Sasaki, H. Frohlich and C. Le Sech 348
Photoluminescence properties of ZnTe homoepitaxial layers grown by synchrotron-radiation-excited growth using nitrogen carrier gas
T. Tanaka, K. Hayashida, S. Wang, Q. Guo, M. Nishio and H. Ogawa 356
Active control of site specificity in ion desorption by core excitation
S. Wada, E.O. Sako, R. Sumii, S. Waki, K. Isari, T. Sekiguchi, T. Sekitani and K. Tanaka 361
Electron paramagnetic resonance induced by K-shell resonance excitation in DNA bases in solid state
A. Yokoya, K. Akamatsu and K. Fujii 366
Microfabrication of high quality polytetrafluoroethylene films by synchrotron radiation
A. Yoshida, E. Matsumoto, H. Yamada, H. Okada and A. Wakahara 370

2.3. Fluorescence analysis

Synchrotron radiation micro-X-ray fluorescence analysis: A tool to increase accuracy in microscopic analysis
F. Adams 375
Peculiar structure of X-ray standing wave lines of Si:As
K. Hayashi, Y. Takahashi, E. Matsubara, M. Takemura, I. Mizushima, H. Tanida and M. Ishii 382
Electron correlation energy of $La_xSr_{1-x}TiO_3$ by high-resolution soft-X-ray emission spectroscopy
T. Higuchi, T. Takeuchi, T. Tsukamoto, Y. Harada, Y. Taguchi, Y. Tokura and S. Shin 386
Chemical characterization using relative intensity of manganese $K\beta'$ and $K\beta_5$ X-ray fluorescence
K. Sakurai and H. Eba 391
Quantitative X-ray fluorescence analysis at the ESRF ID18F microprobe
B. Vekemans, L. Vincze, A. Somogyi, M. Drakopoulos, L. Kempenaers, A. Simionovici and F. Adams 396

2.4. Photoelectron emission spectroscopy

Characterization of Ge-nanocrystal films with photoelectron spectroscopy
C. Bostedt, T. van Buuren, T.M. Willey, A.J. Nelson, N. Franco, T. Möller and L.J. Terminello 402
Photoelectron spectroscopy study on Li substituted NiO using PES beamline installed on Indus-1
A. Banerjee, S.M. Chaudhari, D.M. Phase and B.A. Dasannacharya 406
Electronic structure of β-$FeSi_2$ obtained by maximum entropy method and photoemission spectroscopy
H. Kakemoto, T. Higuchi, Y. Makita, Y. Kino, T. Tsukamoto, S. Shin, S. Wada and T. Tsurumi ... 411
Core-level photoelectron study of Si(111) $\sqrt{7} \times \sqrt{3}$-(Pb, Sn) surface
K. Soda, J. Yuhara, T. Takada, O. Yoshimoto, M. Kato, S. Yagi, K. Morita and M. Kamada 416
Electronic structure of Si(111)$2\sqrt{7} \times 3$-(Pb,Sn) surface
J. Yuhara, S. Yuasa, O. Yoshimoto, D. Nakamura, K. Soda and M. Kamada 422

3. Imaging

3.1. Phase-contrast imaging

Phase-contrast X-ray imaging with synchrotron radiation for materials science applications
A.W. Stevenson, T.E. Gureyev, D. Paganin, S.W. Wilkins, T. Weitkamp, A. Snigirev, C. Rau, I. Snigireva, H.S. Youn, I.P. Dolbnya, W. Yun, B. Lai, R.F. Garrett, D.J. Cookson, K. Hyodo and M. Ando 427

Edge-enhanced radiology with broadband synchrotron X-rays
W.L. Tsai, P.C. Hsu, Y. Hwu, J.H. Je, Y. Ping, H.O. Moser, A. Groso and G. Margaritondo 436
Real-time microradiology of disintegration of iron ore sinteres
J.R. Kim, H.S. Kang, H.J. Lee, J.H. Je, S.K. Jeong, W.-L. Tsai, P.C. Hsu and Y. Hwu 441
Simulation study of spatial resolution in phase-contrast X-ray imaging with Takagi–Taupin equation
I. Koyama and A. Momose 446
Real-time observation of Zn electro-deposition with high-resolution microradiology
W.L. Tsai, P.C. Hsu, Y. Hwu, C.H. Chen, L.W. Chang, J.H. Je and G. Margaritondo 451
Grain boundary imaging, gallium diffusion and the fracture behavior of Al–Zn Alloy – An in situ study
W.L. Tsai, Y. Hwu, C.H. Chen, L.W. Chang, J.H. Je, H.M. Lin and G. Margaritondo 457

3.2. Holography

X-ray holography
G. Faigel, M. Tegze, M. Belakhovsky, S. Marchesini and G. Bortel 464

3.3. X-ray microscopy

Electromigration in integrated circuit interconnects studied by X-ray microscopy
G. Schneider, G. Denbeaux, E. Anderson, W. Bates, F. Salmassi, P. Nachimuthu, A. Pearson, D. Richardson, D. Hambach, N. Hoffmann, W. Hasse and K. Hoffmann 469

4. Combinations of methods

Synchrotron radiation studies of inorganic–organic semiconductor interfaces
D.A. Evans, H.J. Steiner, A.R. Vearey-Roberts, A. Bushell, G. Cabailh, S. O'Brien, J.W. Wells, I.T. McGovern, V.R. Dhanak, T.U. Kampen, D.R.T. Zahn and D. Batchelor 475
Structure of liquid oxides at very high temperatures
C. Landron, L. Hennet, D. Thiaudiere, D.L. Price and G.N. Greaves 481
Using XAFS, EDAX and AFM in comparative study of various natural and synthetic emeralds
P. Parikh, N.L. Saini, S. Dalela, D.M. Bhardwaj, S. Fernandes, R.P. Gupta and K.B. Garg 489
Structural and chemical diagnosis of magnetic multilayers by RAFS and XRF techniques
Z.H. Mai, G.M. Luo, C.X. Liu, M.H. Li, H.W. Jiang, W.Y. Lai, J. Wang, Y.F. Ding, T.P.A. Hase, B.D. Fulthorpe and B.K. Tanner 494
Characterization of zinc oxide nanoparticles encapsulated into zeolite-Y: An in-situ combined X-ray diffraction, XAFS, and SAXS study
F. Meneau, G. Sankar, N. Morgante, S. Cristol, C.R.A. Catlow, J.M. Thomas and G.N. Greaves ... 499
In situ characterization of iron phosphate and bismuth molybdate catalysts prepared by hydrothermal methods: An EDXRD and combined XRD/XAS study
A.M. Beale and G. Sankar 504

5. Facilities

Novel X-ray source based on a tabletop synchrotron and its unique features
H. Yamada 509
Control system for Siam photon source
R. Apiwatwaja, G. Hoyes, G. Isoyama, T. Ishii and W. Pairsuwan 517
Design of a polarised light beamline in the energy range of 30–4000 eV
S.M. Chaudhari, A. Banerjee, D.M. Phase and B.A. Dasannacharya 520
Edge radiation as IR–UV source
K. Shirasawa, N.V. Smolyakov, A. Hiraya and T. Muneyoshi 526

Materials science research at the European Synchrotron Radiation Facility
A. Kvick 531
Singapore Synchrotron Light Source – Status, first results, program
H.O. Moser, E.P. Chew, V.C. Kempson, J.R. Kong, Z.W. Li, T. Nyunt, H.J. Qian, R. Rossmanith, P.H. Tor, O. Wilhelmi, P. Yang, H.W. Zheng and I.J. Underhay 536
Status of Indus-1 and Indus-2 beamlines
R.V. Nandedkar and K.J.S. Sawhney 541
Status of the Siam Photon Source
W. Pairsuwan and T. Ishii 546
The experimental station for white beam X-ray topography at the synchrotron light source ANKA, Karlsruhe
R. Simon and A.N. Danilewsky 550
The X-ray-fluorescence facility at ANKA, Karlsruhe: Minimum detection limits and micro probe capabilities
R. Simon, G. Buth and M. Hagelstein 554
Effects of beamline components (undulator, monochromator, focusing device) on the beam intensity at ID18F (ESRF)
A. Somogyi, M. Drakopoulos, B. Vekemans, L. Vincze, A. Simionovici and F. Adams 559
Beamlines at Siam photon laboratory
P. Songsiriritthigul, W. Pairsuwan, T. Ishii and A. Kakizaki 565
The materials science program of the Kurchatov synchrotron radiation source
V.G. Stankevich 569
Hiroshima Synchrotron Radiation Center – An outline and scientific activities
M. Taniguchi 574

Author index 580